# EMC APPLICATIONS OF THE EMAP5 HYBRID FEM/MOM CODE 

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#### Abstract

EMAP5 is a numerical software package designed to model electromagnetic problems. It employs the finite element method (FEM) to analyze threedimensional volumes, and the method of moments (MOM) to analyze the current distribution on the surface of these volumes. The two methods are coupled through the fields on the dielectric surface. This paper describes the formulation of the EMAP5 code and demonstrates how it can be used to analyze simple printed circuit board configurations.


## I. INTRODUCTION

EMAP5---ElectroMagnetic Analysis Program Version 5 is a 3D numerical electromagnetic modeling code developed at the University of Missouri-Rolla (UMR). The code can be freely downloaded from the world wide web at http://www.emclab.umr.edu/emap5. EMAP5 is a hybrid FEM/MOM code designed primarily to simulate electromagnetic interference (EMI) sources at the printed circuit board level.

Generally, printed circuit boards and their components are composed of many different materials with arbitrary shapes. Thus, the Method of Moments (MOM) does not model this kind of problem efficiently. A hybrid method combining FEM with MOM has been proposed by many researchers [1][2][3] as a means of modeling structures that are both open (i.e. unbounded) and complex. FEM is applied to model the fields within a fictitious boundary containing regions of high complexity, while MOM is used to model the fields on the fictitious boundary. The two methods are coupled by the fields at the dielectric boundary.

Details of the hybrid formulation for EMAP5 are presented in [4][5]. This paper demonstrates how EMAP5 can be used to model 3D microstrip configurations.

## II. FORMULATION

The general structure of interest is shown in Figure 1. A dielectric volume $V_{2}$ has electrical properties $\left(\varepsilon_{2}, \mu_{2}\right)$. It is enclosed by a surface $S_{2}$. A conductive volume $V_{3}$ is enclosed by a conductive surface $\mathrm{S}_{\mathrm{c}}$. The fields within $\mathrm{V}_{3}$ vanish. $\mathrm{V}_{1}$, which denotes the volume outside of $\mathrm{V}_{2}$ and $\mathrm{V}_{3}$, is assumed to be free space, hence has electrical properties $\left(\varepsilon_{0}, \mu_{0}\right) .\left(\mathbf{E}_{1}, \mathbf{H}_{1}\right)$ and $\left(\mathbf{E}_{2}, \mathbf{H}_{2}\right)$ denote the electric and magnetic fields in $\mathrm{V}_{1}$ and $\mathrm{V}_{2}$, respectively. The unit normal vectors for $S_{2}$ and $S_{c}$ are defined pointing outward


Fig. 1. A dielectric obect and a conductive object illuminated by $\mathbf{E}^{\mathrm{i}}, \mathbf{H}^{\mathrm{i}}$ or $\mathbf{J}^{\text {int }}, \mathbf{M}^{\text {int }}$.
toward $\mathrm{V}_{1}$. The structure is excited by an incident wave ( $\mathbf{E}^{\mathrm{i}}$, $\left.\mathbf{H}^{\mathrm{i}}\right)$ or impressed sources $\left(\mathbf{J}^{\text {int }}, \mathbf{M}^{\text {int }}\right)$. The scattered electric and magnetic fields are $\left(\mathbf{E}^{\mathrm{s}}, \mathbf{H}^{\mathrm{s}}\right)$. The dielectric surface $\mathrm{S}_{\mathrm{d}}$, is defined as $S_{2}$ if the conductive body is not adjacent to the dielectric body; Otherwise, $S_{d}=S_{2}-\left(S_{2} \cap S_{c}\right)$. The objective is to solve for the scattered fields $\left(\mathbf{E}^{\mathrm{s}}, \mathbf{H}^{\mathrm{S}}\right)$ or the surface electric current density on $\mathrm{S}_{\mathrm{c}}$.

## A. Discretization of FEM

From the double curl equation in terms of $\mathbf{E}$, the weak form of FEM equation can be expressed as:

$$
\begin{align*}
& \int_{\mathrm{V}_{2}}\left[\left(\frac{\nabla \times \mathbf{E}(\mathbf{r})}{\mathrm{j} \omega \mu_{0} \mu_{\mathrm{r}}}\right) \cdot(\nabla \times \mathbf{w}(\mathbf{r}))+\mathrm{j} \omega_{\in_{0} \in \mathbf{r}} \mathbf{E}(\mathbf{r}) \bullet \mathbf{w}(\mathbf{r})\right] \mathrm{dV} \\
& \quad=\int_{\mathrm{S}_{2}}(\hat{\mathbf{n}} \times \mathbf{H}(\mathbf{r})) \bullet \mathbf{w}(\mathbf{r}) \mathrm{dS}-\int_{\mathrm{V}_{2}}\left[\mathbf{J}^{\text {int } \left.(\mathbf{r})+\frac{\nabla \times \mathbf{M}^{\text {int }}(\mathbf{r})}{\mathrm{j} \omega \mu_{0} \mu_{\mathrm{r}}}\right] \bullet w(\mathbf{r}) \mathrm{dV}}\right. \tag{1}
\end{align*}
$$

where $\mathbf{w}(\mathbf{r})$ is a weighting function.
Tetrahedral elements are used to discretize the volume $\mathrm{V}_{2}$. Basis functions proposed by M. L. Barton and Z. J. Cendes [6] are chosen here. Each basis function is defined within a tetrahedron and is associated with one of the six edges. The electric field $\mathbf{E}$ within volume $\mathrm{V}_{2}$ can be expanded as:

$$
\mathbf{E}(\mathbf{r})=\sum_{\mathrm{n}=1}^{\mathrm{N}_{\mathrm{v}}} \mathrm{En}_{\mathrm{n}} \mathbf{W n}(\mathbf{r})
$$

where $\mathrm{N}_{\mathrm{v}}$ is the total number of interior edges and boundary edges on the dielectric surface, and $\left\{E_{n}\right\}$ is a set of unknown complex scalar coefficients. The weighting functions chosen are $\mathbf{w}_{\mathrm{n}}(\mathbf{r}), \mathrm{n}=1, \ldots \mathrm{~N}_{\mathrm{v}}$. After the weighting functions are applied to Eq. (1), Eq.(1) can be discretized as:

$$
\left[\begin{array}{cc}
\mathrm{A}_{\mathrm{ii}} & \mathrm{~A}_{\mathrm{id}}  \tag{2}\\
\mathrm{~A}_{\mathrm{di}} & \mathrm{~A}_{\mathrm{dd}}
\end{array}\right]\left[\begin{array}{c}
\mathrm{E}_{\mathrm{i}} \\
\mathrm{E}_{\mathrm{d}}
\end{array}\right]=\left[\mathrm{B}_{\mathrm{dd}}\right]\left[\mathrm{J}_{\mathrm{d}}\right]+\left[\mathrm{g}^{\mathrm{int}}\right]
$$

where $\left\{\mathrm{E}_{\mathrm{i}}\right\}$ are the unknown electric fields within the FEM volume. $\left\{\mathrm{E}_{\mathrm{d}}\right\}$ are the unknown equivalent surface magnetic currents on $\mathrm{S}_{\mathrm{d}}$. $\left\{\mathrm{J}_{\mathrm{d}}\right\}$ are the equivalent electric currents on the dielectric surface, which is discussed in later section. $\left\{g^{\text {int }}\right\}$ are the impressed current source terms. $\left\{A_{i i}\right\},\left\{A_{i d}\right\}$, $\left\{\mathrm{A}_{\mathrm{di}}\right\},\left\{\mathrm{A}_{\mathrm{dd}}\right\}$ and $\left\{\mathrm{B}_{\mathrm{dd}}\right\}$ are the coefficient matrices.

## B. Discretization of MoM

The MOM surface integral equation is [7]:

$$
\begin{align*}
& \mathbf{E}^{\text {inc }}(\mathbf{r})=\frac{1}{2} \mathbf{E}(\mathbf{r})+\int_{S}\left\{\mathbf{M}\left(\mathbf{r}^{\prime}\right) \times \nabla^{\prime} \mathrm{G}_{0}\left(\mathbf{r}, \mathbf{r}^{\prime}\right)\right. \\
& \left.\quad+\mathrm{j}_{\mathrm{k}} \eta_{0} \mathbf{J}\left(\mathbf{r}^{\prime}\right) \mathrm{G}_{0}\left(\mathbf{r}, \mathbf{r}^{\prime}\right)-\mathrm{j} \frac{\eta_{0}}{\mathrm{k}_{0}} \nabla^{\prime} \bullet \mathbf{J}\left(\mathbf{r}^{\prime}\right) \nabla^{\prime} \mathrm{G}_{0}\left(\mathbf{r}, \mathbf{r}^{\prime}\right)\right\} \mathrm{dS} \tag{3}
\end{align*}
$$

where $\mathbf{r} \in S, \quad S=S_{c} \cup S_{2}, \eta_{0}$ and $k_{0}$ are the intrinsic impedance and wavenumber in free space, respectively, and

$$
\operatorname{Go}\left(\mathbf{r}, \mathbf{r}^{\prime}\right)=\frac{\mathrm{e}^{-\mathrm{j} \mathrm{k}_{0}\left|\mathbf{r}-\mathbf{r}^{\prime}\right|}}{4 \pi\left|\mathbf{r}-\mathbf{r}^{\prime}\right|}
$$

is the Green's function in free space. The equivalent surface electric and magnetic currents are defined as:

$$
\begin{array}{ll}
\mathbf{J}\left(\mathbf{r}^{\prime}\right)=\hat{\mathbf{n}} \times \mathbf{H}\left(\mathbf{r}^{\prime}\right) & \mathbf{r}^{\prime} \text { on } S \\
\mathbf{M}\left(\mathbf{r}^{\prime}\right)=\mathbf{E}\left(\mathbf{r}^{\prime}\right) \times \hat{\mathbf{n}} & \mathbf{r}^{\prime} \text { on } \mathrm{S}_{\mathrm{d}}
\end{array}
$$

$\mathbf{M}\left(\mathbf{r}^{\prime}\right)$ vanishes on $\mathrm{S}_{\mathrm{c}} . \mathbf{J}\left(\mathbf{r}^{\prime}\right)$ and $\mathbf{M}\left(\mathbf{r}^{\prime}\right)$ can be approximated by using the triangular basis function $\mathbf{f}_{\mathrm{n}}(\mathbf{r})$ proposed by S . M. Rao et al. [8]. On surface $S_{d}$, the MOM basis function $\mathbf{f}_{\mathrm{n}}(\mathbf{r})$ and the FEM basis function $\mathbf{w}_{\mathrm{n}}(\mathbf{r})$ are related by:

$$
\mathbf{w}_{\mathrm{n}}(\mathbf{r})=\hat{\mathbf{n}} \times \mathbf{f}_{\mathrm{n}}(\mathbf{r}) \quad \mathbf{r} \in \mathrm{S}_{\mathrm{d}}
$$

$\mathbf{J}\left(\mathbf{r}^{\prime}\right), \mathbf{M}\left(\mathbf{r}^{\prime}\right)$ can be expanded as:

$$
\begin{aligned}
& \mathbf{J}\left(\mathbf{r}^{\prime}\right)=\hat{\mathbf{n}} \times \mathbf{H}\left(\mathbf{r}^{\prime}\right)=\sum_{\mathrm{n}=1}^{\mathrm{N}_{\mathrm{s}}} \mathrm{~J}_{\mathrm{n}} \mathbf{f}_{\mathrm{n}}\left(\mathbf{r}^{\prime}\right) \\
& \mathbf{M}\left(\mathbf{r}^{\prime}\right)=\mathbf{E}\left(\mathbf{r}^{\prime}\right) \times \hat{\mathbf{n}}=\sum_{\mathrm{n}=1}^{\mathrm{N}_{\mathrm{d}}} \operatorname{En} \mathbf{W n}_{\mathrm{n}}\left(\mathbf{r}^{\prime}\right) \times \hat{\mathbf{n}}=\sum_{\mathrm{n}=1}^{\mathrm{N}_{\mathrm{d}}} \operatorname{En} \mathbf{f}_{\mathrm{n}}\left(\mathbf{r}^{\prime}\right)
\end{aligned}
$$

where $N_{s}$ is the total number of edges on the surface $S$, and $N_{d}$ is the total number of edges on the surface $S_{d}$. $\left\{J_{n}\right\}$ and $\left\{E_{n}\right\}$ are unknown complex scalar coefficients. The weighting functions chosen are $\mathbf{f}_{\mathrm{n}}(\mathbf{r}), \mathrm{n}=1, \ldots \mathrm{~N}_{\mathrm{s}}$. After the weighting functions are applied to Eq. (3), Eq. (3) can be discretized into,

$$
\left[\begin{array}{ll}
\mathrm{Cdd} & \mathrm{Cdc}  \tag{4}\\
\mathrm{Ccd} & \mathrm{Ccc}
\end{array}\right]\left[\begin{array}{l}
\mathrm{J}_{\mathrm{d}} \\
\mathrm{~J}_{\mathrm{c}}
\end{array}\right]=\left[\begin{array}{ll}
\mathrm{Ddd} & 0 \\
\mathrm{Dcd} & 0
\end{array}\right]\left[\begin{array}{c}
\mathrm{Ed}_{d} \\
0
\end{array}\right]+\left[\begin{array}{c}
\mathrm{F}_{\mathrm{d}}^{\mathrm{i}} \\
\mathrm{~F}_{\mathrm{c}}^{\mathrm{i}}
\end{array}\right]
$$

where $\left\{\mathrm{J}_{\mathrm{d}}\right\}$ and $\left\{\mathrm{J}_{\mathrm{c}}\right\}$ are the unknown equivalent surface
electric currents on $S_{d}$ and $S_{c}$ respectively. $\left\{E_{d}\right\}$ are the unknown equivalent surface magnetic currents on $\mathrm{S}_{\mathrm{d}}$. $\left\{\mathrm{C}_{\mathrm{dd}}\right\},\left\{\mathrm{C}_{\mathrm{dc}}\right\},\left\{\mathrm{C}_{\mathrm{cd}}\right\},\left\{\mathrm{C}_{\mathrm{cc}}\right\},\left\{\mathrm{D}_{\mathrm{dd}}\right\}$ and $\left\{\mathrm{D}_{\mathrm{cd}}\right\}$ are coefficient matrices. $\left\{\mathrm{F}_{\mathrm{i}}^{\mathrm{d}}\right\}$ and $\left\{\mathrm{F}_{\mathrm{c}}^{\mathrm{i}}\right\}$ are forcing terms due to the incident wave.

The FEM Eq. (2) and the MOM Eq. (4) are coupled through $\left\{\mathrm{E}_{\mathrm{d}}\right\}$ and $\left\{\mathrm{J}_{\mathrm{d}}\right\}$. By solving the two equations, all fields within the FEM region and the surface equivalent currents can be obtained. Details of how to construct the matrix equation and solve it are provided in [4][5].

## III. NUMERICAL RESULTS

Two numerical examples are provided in this section to demonstrate the application of the EMAP5 code to printed circuit board geometries.

## A. Determining the Characteristic Impedance of a Microstrip Geometry

This example simulates a microstrip line on a printed circuit board. The geometry of the structure is shown in Figure 2. The board is made of a dielectric with $\varepsilon_{\mathrm{r}}=4.0$. The trace is excited by a 1 V source at one end, and is terminated by a resistor at the other end. To determine the characteristic impedance $\mathrm{Z}_{0}$ of the transmission line, we need to determine the input impedance when the load side is shorted or open, respectively. The input impedance $Z_{\text {in }}$ of a transmission line is given by,

$$
\mathrm{Z}_{\mathrm{in}}=\mathrm{Z}_{0} \frac{\mathrm{Z}_{\mathrm{L}}+\mathrm{j} \mathrm{Z}_{0} \tan (\beta l)}{\mathrm{Z}_{0}+\mathrm{j} \mathrm{Z}_{\mathrm{L}} \tan (\beta l)}
$$

where $\mathrm{Z}_{\mathrm{L}}$ is the load impedance; $\beta$ is the wavenumber; $l$ is the length of the transmission line. When the load side is shorted, the input impedance is given by,

$$
\left(\mathrm{Z}_{\text {in }}\right)_{\text {short }}=\mathrm{j} \mathrm{Z}_{0} \tan (\beta l)
$$

when the load side is open, the input impedence is given by,

$$
\left(\mathrm{Z}_{\mathrm{in}}\right)_{\text {open }}=-\mathrm{j} \frac{\mathrm{Z}_{0}}{\tan (\beta l)}
$$

Thus, the characteristic impedance is given by,

$$
\mathrm{Z}_{0}=\sqrt{\left(\mathrm{Z}_{\text {in }}\right)_{\text {short }}\left(\mathrm{Z}_{\text {in }}\right)_{\text {open }}}
$$

Since the source is electrically short and small, it can be modeled as a current filament [9]. The source can be expressed as,

$$
\mathbf{J}^{\mathrm{int}}=I \delta\left(\mathrm{x}-\mathrm{x}_{\mathrm{f}}\right) \delta\left(\mathrm{y}-\mathrm{y}_{\mathrm{f}}\right) \hat{\mathbf{z}}
$$

where ( $\mathrm{x}_{\mathrm{f}}, \mathrm{y}_{\mathrm{f}}$ ) specifies its position, $I$ denotes the electric current magnitude, and $\delta(\mathrm{x})$ is the Dirac delta function. $\mathbf{J}^{\text {int }}$ is the impressed current source that is included in Eq. (1) as the source term. After the $\mathbf{E}$ fields along the source edges are obtained, the voltage drop along the current filament can be calculated. Thus, the input impedance $\mathrm{Z}_{\text {in }}$ can be obtained.

(a)
(c)

Fig. 2. Grounded printed circuit board with an active trace.
(a) y-z plane view.
(b) x-z plane view. and (c) 3D view.

Table 1 shows inductance and capacitance obtained by EMAP5 when the load side is shorted or open, respectively. The characteristic impedance $\mathrm{Z}_{0}$ of the trace then can be determined. Three frequencies have been investigated. At each frequency, the calculated value of $\mathrm{Z}_{0}$ is $56.4 \Omega$. We can put a $56.4 \Omega$ resistor at the load side to terminate the transmission line. Theoretically, there should be no reflection if $\mathrm{Z}_{0}$ is $56.4 \Omega$. Figure 3 shows the numerical results obtained by EMSIM when the trace is terminated with a $56.4 \Omega$ resistor. It is evident that the transmission line is almost perfectly matched.

## B. Determining the Input Impedance of a Microstrip Line with a Resistive Load.

In this example, the configuration is the same as shown in Figure 2. Now however, the load is a $50 \Omega$ resistor. A load $\mathrm{Z}_{\mathrm{L}}$ can be modeled as an element with finite conductivity


Fig. 3. The input impedance obtained by EMSIM when the trace in Fig. 2. is terminated by a $56.4 \Omega$ resistor.
given by $\sigma=l /\left(\mathrm{Z}_{\mathrm{L}} \mathrm{S}\right)$, where $l$ is its length, and S is the cross section. If the load is treated as a lumped element, its contribution to the finite element matrix is as follows [8]:

$$
\left[\mathrm{K}^{\mathrm{e}}\right]=\frac{l^{2}}{\mathrm{ZL}} \iint\{\mathrm{w}\}\{\mathrm{w}\}^{\mathrm{T}} \delta(\mathrm{x}-\mathrm{xL})(\mathrm{y}-\mathrm{yL}) \mathrm{dx} d \mathrm{y}
$$

where $\left(\mathrm{x}_{\mathrm{L}}, \mathrm{y}_{\mathrm{L}}\right)$ is the position of the load impedance. Only edges coinciding with the load are affected by the load.

Figure 4 shows the impedance obtained by EMAP5 and compares them with results obtained by EMSIM. Since the characteristic impedance of the microstrip line is about $56.4 \Omega$, the $50 \Omega$ load does not match the microstrip line perfectly. As shown in Figure 4, the input impedance is not exactly $50 \Omega$ due to the mismatch. The EMAP5 results agree very well with the EMSIM results for this example.

Table 1. Characteristic impedance obtained by EMAP5.

| Source Frequency <br> $(\mathrm{MHz})$ | $\left(\mathrm{Z}_{\text {in }}\right)_{\text {open }}(\Omega)$ | $\left(\mathrm{Z}_{\text {in }}\right)_{\text {short }}(\Omega)$ | $\mathrm{Z}_{0}(\Omega)$ |
| :--- | :--- | :--- | :--- |
| 300 | -j 187 | +j 17 | 56.4 |
| 500 | -j 106 | +j 30 | 56.4 |
| 700 | -j 69 | +j 46 | 56.3 |



Fig. 4. The input impedance of the structure in Fig 2. when the trace is terminated by a $50 \Omega$ resistor.

## IV. CONCLUSION

This paper introduces the hybrid FEM/MOM code called EMAP5. Examples of the application of EMAP5 to printed circuit geometries were presented and good agreement was achieved with theoretical results and results obtained using EMSIM.

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